

## ABSTRACT OF THE DISCLOSURE

An interface detection apparatus detects a position of a hidden interface between first and second materials, the first material having a different physical property from the second material. The apparatus encompasses (a) an irradiation mechanism configured to irradiate an electromagnetic wave onto a sample implemented by the first and second materials, (b) a detection mechanism configured to detect the electromagnetic wave that has passed through the sample, and (c) a traveling mechanism configured to change the relative position of the hidden interface with respect to the position of the detection mechanism.